



LCIE



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TEST REPORT

N°: 24111489-806170-A(FILE#9376726-NOR)

Version: 01

Subject Electromagnetic compatibility tests according to the standards:
FCC CFR 47 Part 15, Subpart B
ANSI C63.4 / ANSI C63.4a
ICES-003

Issued to ENLAPS
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FRANCE

Apparatus under test

↗ Product	Timelapse digital cameras
↗ Trade mark	enlaps™
↗ Manufacturer	ENLAPS
↗ Model under test	Tikee 4
↗ Serial number	T-4TK-4Q-E01492
↗ FCCID	2ASLI-TIKEE003
↗ IC	24785-TIKEE003

Conclusion See Test Program chapter

Test date	November 04, 2024 to November 14, 2024
Test location	LCIE Grenoble
FCC Test site	FR0008 - 918017 (MOI)
ISED Test site	6500A (MOI)
Sample receipt date	November 04, 2024
Composition of document	25 pages
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Version	Date	Author	Modification
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Each new edition of this test report replaces and cancels the previous edition. The control of the old editions of report is under responsibility of client.



SUMMARY

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1. TEST PROGRAM

EMISSION TEST	LIMITS			RESULTS (Comments)
Limits for conducted disturbance 150kHz-30MHz FCC §15.107 / ICES-003	Access: AC power			PASS
	Frequency	Quasi-peak	Average	
	150-500kHz	66 to 56 dBµV	56 to 46 dBµV	
	0.5-5MHz	56 dBµV	46 dBµV	
	5-30MHz	60 dBµV	50 dBµV	
Radiated emissions 30MHz-1GHz FCC §15.109	Access: Enclosure port of ancillary equipment			PASS
	Frequency	Quasi-peak @3m		
	30MHz-88MHz	40.0 dBµV/m		
	88MHz-216MHz	43.5 dBµV/m		
	216MHz-960MHz	46.0 dBµV/m		
Above 960MHz	54.0 dBµV/m			
Radiated emissions 30MHz-1GHz ICES-003	Access: Enclosure port of ancillary equipment			PASS
	Frequency	Quasi-peak @3m		
	30MHz-88MHz	40.0 dBµV/m		
	88MHz-216MHz	43.5 dBµV/m		
	216MHz-230MHz	46.0 dBµV/m		
	230MHz-960MHz	47.0 dBµV/m		
Above 960MHz	54.0 dBµV/m			
Radiated emissions 1GHz-14GHz* FCC §15.109 / ICES-003	Access: Enclosure port of ancillary equipment			PASS
	Frequency	Peak @3m	Average @3m	
	1- 14GHz	74.0 dBµV/m	54.0 dBµV/m	

NA: Not Applicable / NP: Not Performed, not requested by the customer (It cannot be taken into account for the declaration of conformity)

Ⓐ: Divergence, the last version is used to make it possible to test the product with the standard which describes the current state of the art and thus to answer as well as possible his environment of final use. If this test is covered by the COFRAC accreditation, the declaration of conformity for product standard only are carried out outside the framework of accreditation.

***§15.33:** The highest internal source of a testing device is defined like more the highest frequency generated or used in the testing device or on which the testing device works or agrees.

- If the highest frequency of the internal sources of the testing device is lower than 108 MHz, measurement must be only performed until 1GHz.

- If the highest frequency of the internal sources of the testing device ranges between 108 MHz and 500 MHz, measurement must be only performed until 2GHz.

- If the highest frequency of the internal sources of the testing device ranges between 500 MHz and 1 GHz, measurement must be only performed until 5GHz.

If the highest frequency of the internal sources of the testing device is above 1 GHz, measurement must be only performed until 5 times the highest frequency or 40 GHz, while taking smallest of both.

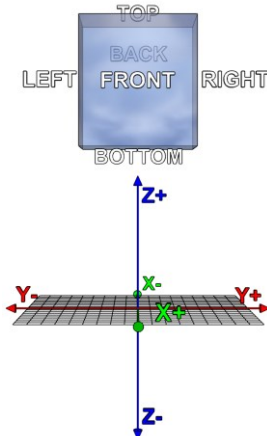
Special condition for intentional radiator:

- For a composite system comprised of a digital device using a clock frequency of 1 GHz as the highest frequency for the digital logic and an intentional radiator operating at 2.4 GHz, the composite is required to be investigated to the upper frequency of 24 GHz (in this case, 10 times the intentional radiator frequency is the higher frequency).
- For a composite system comprised of a digital device using a clock frequency of 2 GHz as the highest frequency for the digital logic and an intentional radiator operating at 913 MHz, the composite is required to be investigated to the upper frequency of 10 GHz (in this case, 5 times the unintentional radiator clock frequency is the higher frequency).

2. EQUIPMENT UNDER TEST: CONFIGURATION (DECLARED BY PROVIDER)

2.1. HARDWARE IDENTIFICATION (EUT AND AUXILIARIES)

Equipment under test (EUT):

Model under test :	Tikee 4		
Serial Number:	T-4TK-4Q-E01492		
			
Dimensions:	18cm x 18cm x 8cm (Length x Width x Height)		
Type :	Table-Top		

Power supply:

For measurement with different voltage, it will be presented in test method.

Name	Type	Rating	Reference / Sn	Comments
Supply1	Battery	3.6Vdc [2.5Vdc-4.2Vdc]	/	Internal battery charged by USB-C or proprietary connector
Supply2	Solar Panel	/	/	/
Supply3	AC	100-240V/50-60Hz	Intertek MX15Z-0502500VX E467127	Proprietary, No provided by manufacturer

NC: Not communicated by provider

**Inputs/outputs - Cable:**

Access	Type	Length used (m)	Declared <3m	Shielded	Comments
Supply1	Battery	/	/	/	/
Supply2	AC	2	No	Yes	/
Supply3	Solar Panel	/	/	/	/
Access1	μUSB connector	None	NA	NA	No
Access2	μSD connector	None	NA	NA	NA
Access3	SIM connector	None	NA	NA	NA

NC: Not communicated by provider

Auxiliary equipment used during test:

Type	Reference	Sn	Comments
Wifi Rooter	ASUS RT-AC68U	/	/
Laptop	ASUS Vivobook S530F	/	Test Laptop (communication with EUT)

NC: Not communicated by provider



2.2. EUT CONFIGURATION

Hardware information			
Highest internal frequency (PLL, Quartz, Clock, Microprocessor...):	F_{Highest}:	2690	MHz
Firmware (if applicable):	V. :	6	
Software (if applicable):	V. :	NA	

NC: Not communicated by provider

Test mode	Description of test mode
Test mode 1	Permanent emission with modulation on a fixed channel in the data rate that produced the highest power. 20dBm

2.3. EQUIPMENT MODIFICATIONS DURING THE TESTS

None



2.4. FIELD STRENGTH CALCULATION

The field strength is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain (if any) from the measured reading. The basic equation with a sample calculation is as follow:

$$FS = RA + AF + CF - AG$$

Where
FS = Field Strength
RA = Receiver Amplitude
AF = Antenna Factor
CF = Cable Factor
AG = Amplifier Gain

2.5. TEST DISTANCE EXTRAPOLATION – FCC/ISED

The field strength is extrapolated to the new measurement distance using formula from FCC Part15.31 (f) and §6.5-6.6 RSS-GEN:

Below 30MHz,

$$FS_{\text{limit}} = FS_{\text{max}} - 40 \log \left(\frac{d_{\text{limit}}}{d_{\text{measure}}} \right)$$

Above 30MHz,

$$FS_{\text{limit}} = FS_{\text{max}} - 20 \log \left(\frac{d_{\text{limit}}}{d_{\text{measure}}} \right)$$

Where:

FS_{limit} is the calculation of field strength at the limit distance, expressed in dBμV/m

FS_{max} is the measured field strength, expressed in dBμV/m

d_{measure} is the distance of the measurement point from the EUT

d_{limit} is the reference limit distance

2.6. CALIBRATION DATE

The calibration intervals are extended at 12+2 months. This extended interval is based on the fact that there is sufficient calibration data to statistically establish a trend or based on experience of use of the test equipment to assure good measurement results for a longer period. The symbol -/- replaces the date for equipment checking before test or that have none impact on the test or that have no calibration required by the standard.

3. MEASUREMENT OF CONDUCTED EMISSION

3.1. TEST CONDITIONS

Date of test : November 07, 2024
 Test performed by : Akram HAKKARI
 Relative humidity (%) : 33
 Ambient temperature (°C) : 21

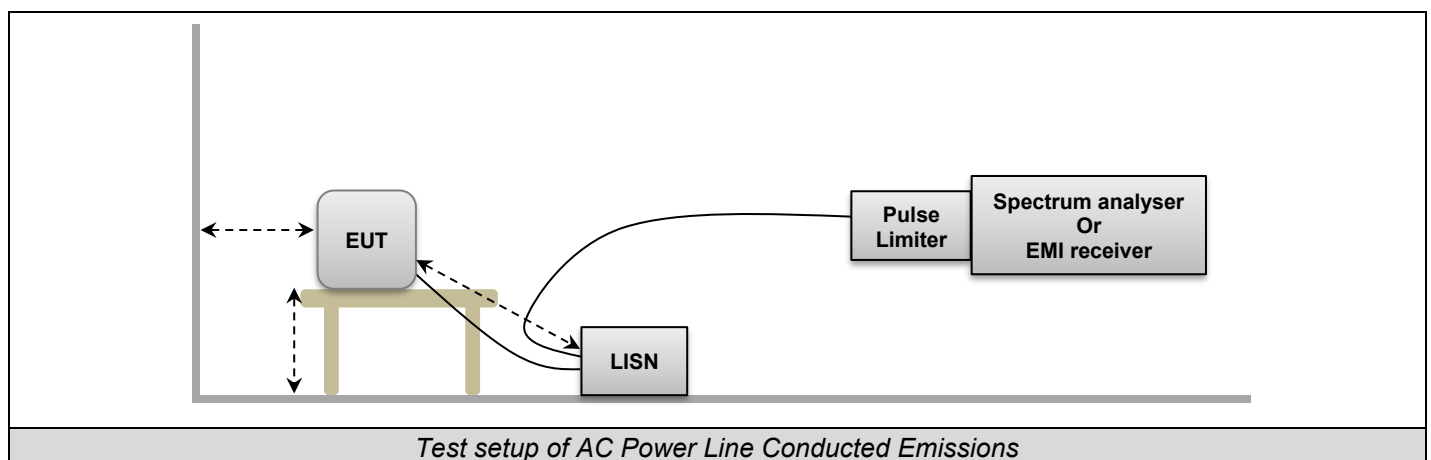
3.2. TEST SETUP

Test procedure:
 ANSI C63.4 & FCC Part 15 subpart B

The EUT and auxiliaries are set 80cm above the ground on the non-conducting table (Table-top equipment) at 80cm from the LISN, the cable has been shorted to 1meter length. The distance between the EUT and the vertical ground plane is 40cm. Measurement is made with a receiver in peak mode. This was followed by a Quasi-Peak, i.e. CISPR measurement for any strong signal. If the average limit is met when using a Quasi-Peak detector, the EUT shall be deemed to meet both limits and measurement with the average detector is unnecessary. Interconnecting cables and equipment were moved to position that maximized emission. The EUT is powered like specified in following table, through a LISN (measure); auxiliaries are powered by another LISN.

Frequency range:	150kHz to 30MHz	
Test:	Pre-Characterization	Qualification
RBW Filter:	10kHz	9kHz
Detector:	Peak & Average	QPeak & Cispr Average
Mode:	Linear Scan	

Type	Measurement performed:	
☒ AC / ☐ DC (Auxiliary used)	☒ 120VAC/60Hz	☒ 240VAC/50Hz
☐ USB (Laptop auxiliary)	☐ 120VAC/60Hz (Laptop auxiliary)	☐ 240VAC/50Hz (Laptop auxiliary)



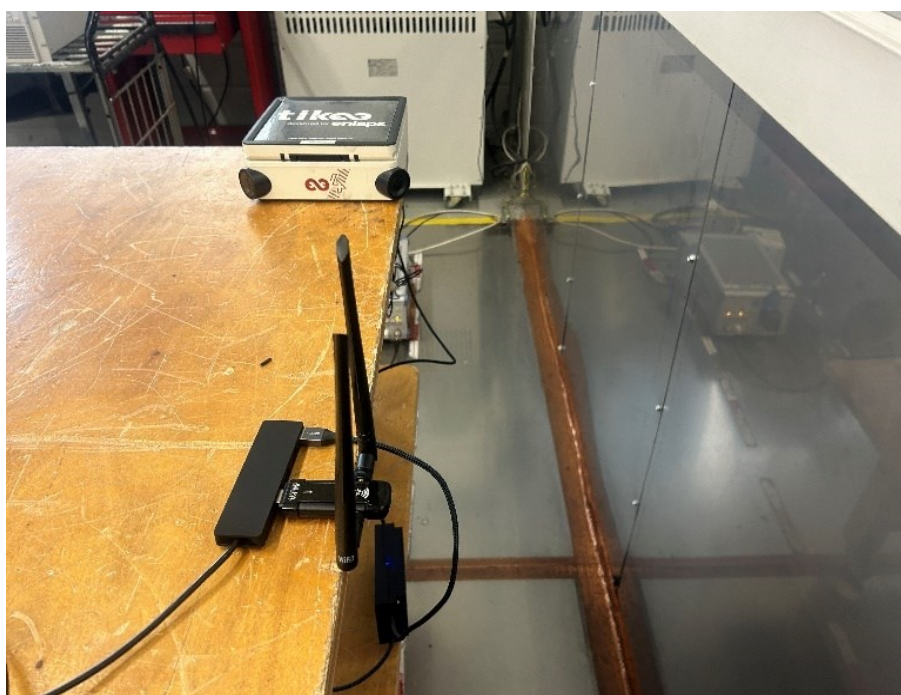
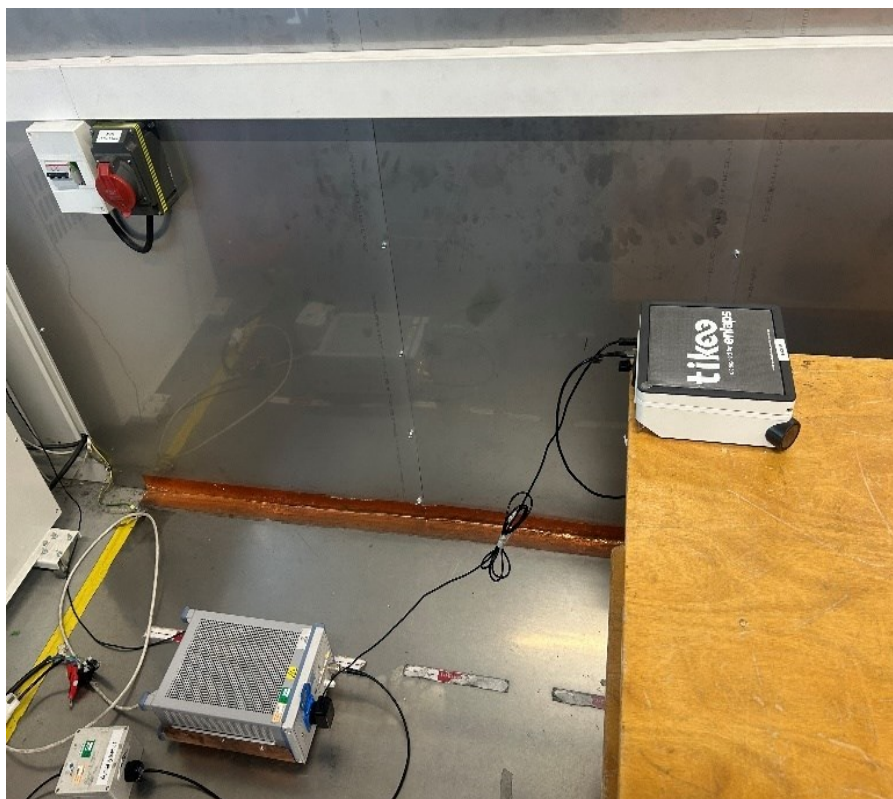


Photo of AC Power Line Conducted Emissions



3.3. TEST EQUIPMENT LIST

TEST EQUIPMENT USED					
Description	Manufacturer	Model	Identifier	Cal_Date	Cal_Due
BAT EMC	NEXIO	v3.21.0.32	L1000115	-/-	-/-
Cable + self	—	—	A5329578	05/24	05/26
EMC comb generator	LCIE SUD EST	—	A3169098	-/-	-/-
LISN	ROHDE & SCHWARZ	ENV216	C2320291	08/24	08/25
Receiver 20Hz – 8GHz	ROHDE & SCHWARZ	ESU8	A2642019	03/23	03/25
Thermo-hygrometer (PM1/2/3)	KIMO	HQ 210	B4206022	05/23	05/25
Transient limiter	ROHDE & SCHWARZ	ESH3-Z2	A7122204	07/24	07/26

3.4. DIVERGENCE, ADDITION OR SUPPRESSION ON THE TEST SPECIFICATION

None

3.5. TEST RESULTS – RUNNING MODE N°1

Mains terminals:

SUPPLY1

Measurements are performed on the phase (L1) and neutral (N) of the power line.

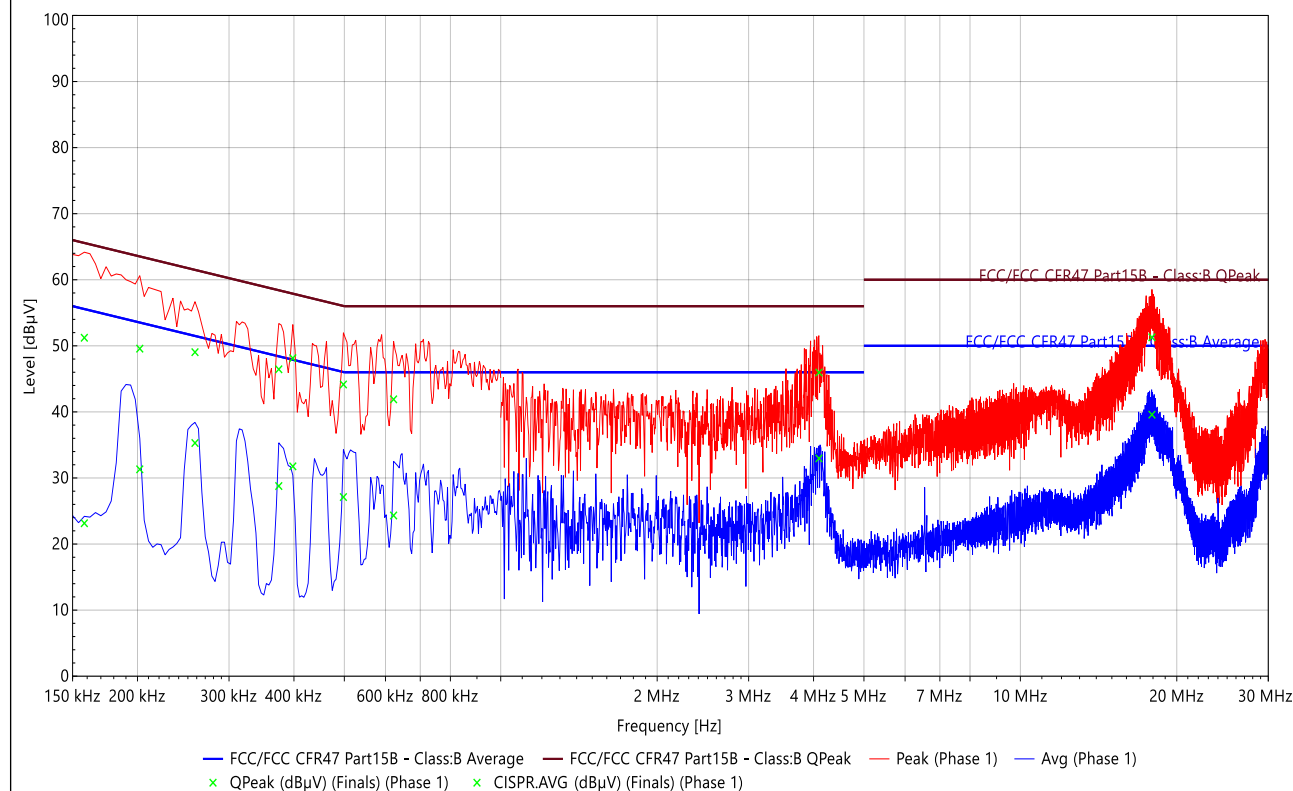
Results: (PEAK detection)

Graph identifier	Line	Comments
Emc# 1	Neutral	120VAC/60Hz See below
Emc# 2	Phase	120VAC/60Hz See below
Emc# 3	Neutral	240VAC/50Hz See below
Emc# 4	Phase	240VAC/50Hz See below

Conducted Emissions

Graph name: Emc#1
Frequency range: 150 kHz to 30 MHz

ESU8 - (RSIL) [150k-30M]Hz - P 120V/60Hz

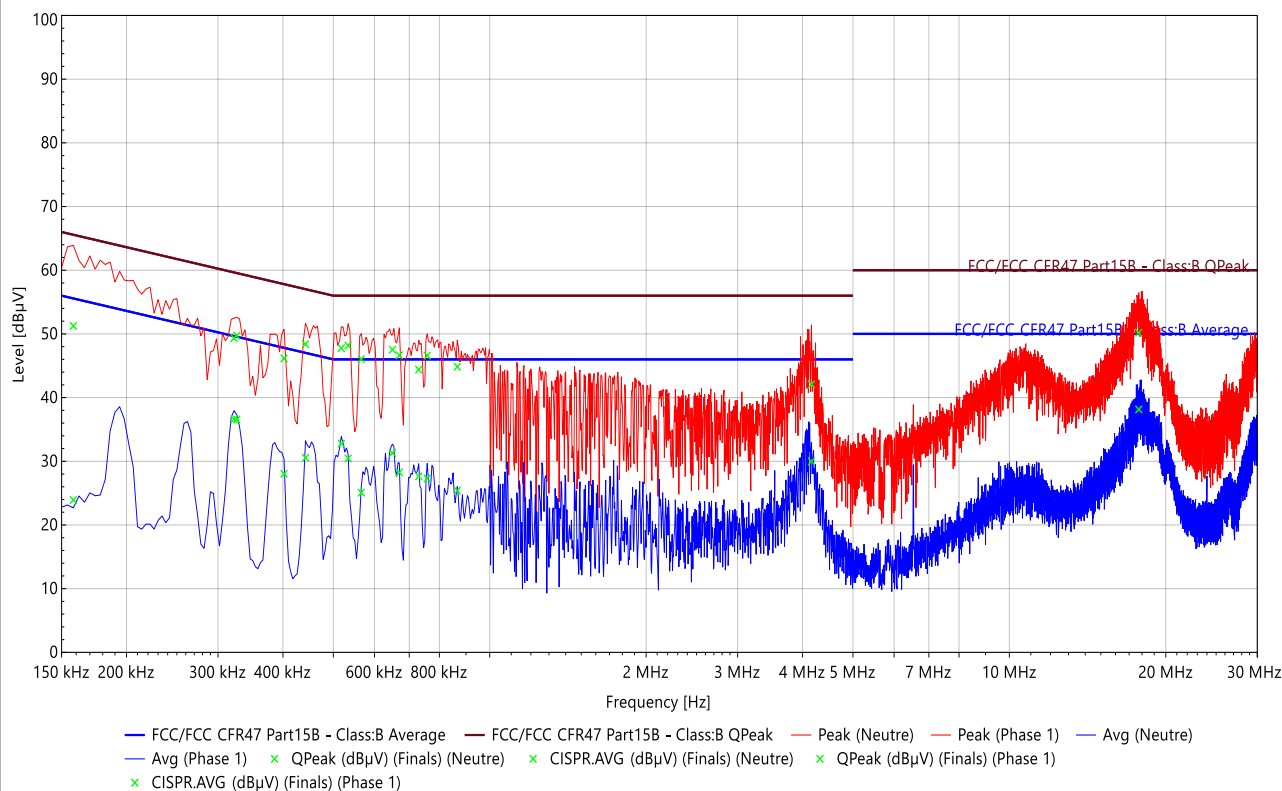


Frequency	QP Level (dBμV)	Lim.QP (dBμV)	QP-Lim.QP (dB)	CAVG Level (dBμV)	Lim.CAVG (dBμV)	CAVG-Lim.CAVG (dB)	Correction (dB)
158.000 kHz	51.22	65.57	-14.34	23.15	55.57	-32.42	19.77
202.000 kHz	49.57	63.53	-13.96	31.31	53.53	-22.21	19.72
258.000 kHz	49.04	61.50	-12.46	35.29	51.50	-16.20	19.50
374.000 kHz	46.45	58.41	-11.96	28.78	48.41	-19.63	19.88
398.000 kHz	48.13	57.90	-9.76	31.76	47.90	-16.13	19.90
498.000 kHz	44.15	56.03	-11.88	27.11	46.03	-18.93	19.92
622.000 kHz	41.90	56.00	-14.10	24.32	46.00	-21.68	19.88
4.096 MHz	45.955	56	-10.045	32.958	46	-13.042	19.772
17.916 MHz	51.287	60	-8.713	39.58	50	-10.42	20.59

Conducted Emissions

Graph name: Emc#2
Frequency range: 150 kHz to 30 MHz

ESU8 - (RSIL) [150k-30M]Hz - N 120V/60Hz

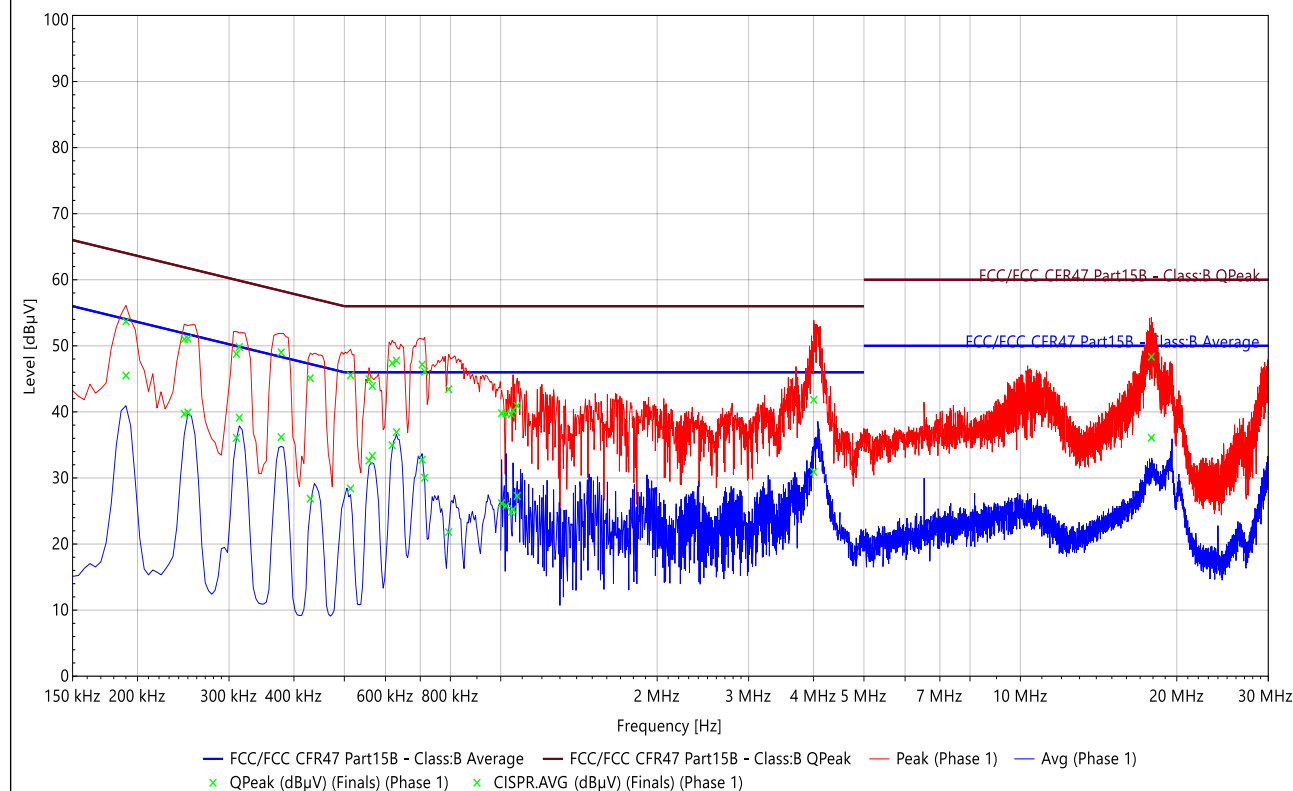


Frequency	QPeak (dBμV)	Lim.QPeak (dBμV)	QPeak-Lim.QPeak (dB)	CISPR.AVG (dBμV)	Lim.CISPR.AVG (dBμV)	CISPR.AVG-Lim.CISPR.AVG (dB)	Correction (dB)
158 kHz	51.25	65.568	-14.319	23.919	55.568	-31.649	19.767
322 kHz	49.343	59.655	-10.312	36.589	49.655	-13.066	19.716
326 kHz	49.712	59.552	-9.841	36.555	49.552	-12.997	19.717
402 kHz	46.152	57.812	-11.66	28.026	47.812	-19.786	19.898
442kHz	48.39	57.024	-8.634	30.552	47.024	-16.473	19.924
518 kHz	47.767	56	-8.233	32.777	46	-13.223	19.907
534 kHz	48.182	56	-7.818	30.444	46	-15.556	19.901
566 kHz	46.037	56	-9.963	25.08	46	-20.92	19.908
650 kHz	47.517	56	-8.483	31.295	46	-14.705	19.849
670 kHz	46.643	56	-9.357	28.255	46	-17.745	19.834
730 kHz	44.401	56	-11.599	27.638	46	-18.362	19.807
758 kHz	46.593	56	-9.407	27.296	46	-18.704	19.796
866 kHz	44.835	56	-11.165	25.388	46	-20.612	19.757
4.16 MHz	42.077	56	-13.923	29.976	46	-16.024	19.776
17.744 MHz	50.18	60	-9.82	38.146	50	-11.854	20.582

Conducted Emissions

Graph name: Emc#3
Frequency range: 150 kHz to 30 MHz

ESU8 - (RSIL) [150k-30M]Hz - P 240V/50Hz



Frequency	QPeak (dBμV)	Lim.QPeak (dBμV)	QPeak-Lim.QPeak (dB)	CISPR.AVG (dBμV)	Lim.CISPR.AVG (dBμV)	CISPR.AVG-Lim.CISPR.AVG (dB)	Correction (dB)
190 kHz	53.702	64.037	-10.334	45.513	54.037	-8.523	19.826
246 kHz	51.001	61.891	-10.89	39.7	51.891	-12.191	19.494
250 kHz	51.077	61.757	-10.68	39.916	51.757	-11.842	19.478
310 kHz	48.779	59.97	-11.191	36.075	49.97	-13.896	19.73
314 kHz	49.816	59.864	-10.048	39.128	49.864	-10.736	19.728
378 kHz	49.012	58.323	-9.311	36.193	48.323	-12.13	19.88
430 kHz	45.112	57.253	-12.14	26.874	47.253	-20.379	19.925
514 kHz	45.535	56	-10.465	28.413	46	-17.587	19.914
558 kHz	44.95	56	-11.05	32.625	46	-13.375	19.916
566 kHz	43.929	56	-12.071	33.341	46	-12.659	19.914
618 kHz	47.373	56	-8.627	34.955	46	-11.045	19.879
630 kHz	47.78	56	-8.22	36.95	46	-9.05	19.873
706 kHz	47.16	56	-8.84	32.771	46	-13.229	19.826
714 kHz	46.078	56	-9.922	30.053	46	-15.947	19.822
794 kHz	43.43	56	-12.57	21.812	46	-24.188	19.793
1.004 MHz	39.793	56	-16.207	26.173	46	-19.827	19.733
1.024 MHz	39.74	56	-16.26	25.783	46	-20.217	19.719

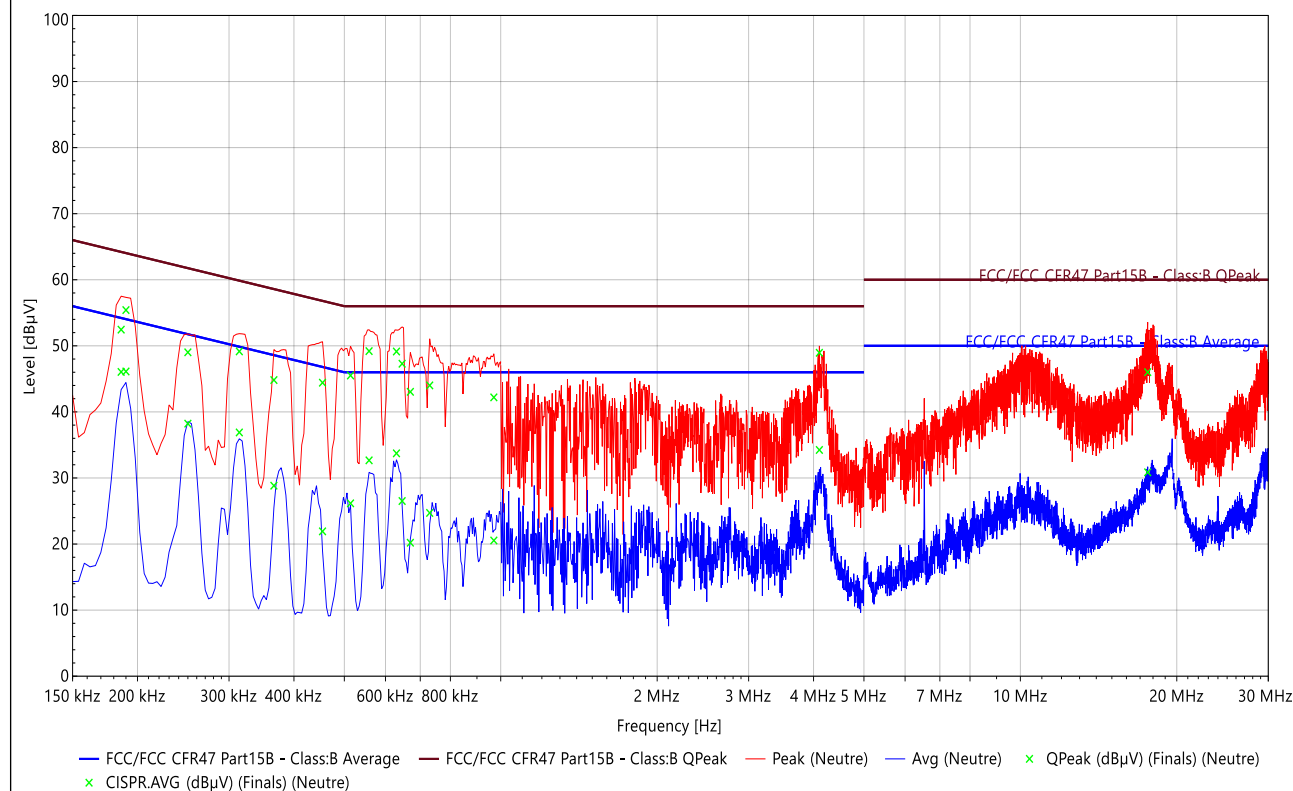


Frequency	QPeak (dBμV)	Lim.QPeak (dBμV)	QPeak- Lim.QPeak (dB)	CISPR.AVG (dBμV)	Lim.CISPR.AVG (dBμV)	CISPR.AVG- Lim.CISPR.AVG (dB)	Correction (dB)
1.048 MHz	39.634	56	-16.366	24.822	46	-21.178	19.71
1.056 MHz	40.234	56	-15.766	25.267	46	-20.733	19.709
1.076 MHz	40.926	56	-15.074	27.267	46	-18.733	19.711
4.003999 MHz	41.83	56	-14.17	30.934	46	-15.066	19.766
17.872 MHz	48.348	60	-11.652	36.081	50	-13.919	20.588

Conducted Emissions

Graph name: Emc#4
Frequency range: 150 kHz to 30 MHz

ESU8 - (RSIL) [150k-30M]Hz - N 240V/50Hz



Frequency	QPeak (dBμV)	Lim.QPeak (dBμV)	QPeak-Lim.QPeak (dB)	CISPR.AVG (dBμV)	Lim.CISPR.AVG (dBμV)	CISPR.AVG-Lim.CISPR.AVG (dB)	Correction (dB)
186 kHz	52.448	64.213	-11.765	46.048	54.213	-8.166	19.87
190 kHz	55.407	64.037	-8.63	46.121	54.037	-7.915	19.823
250 kHz	49.02	61.757	-12.737	38.216	51.757	-13.542	19.476
314 kHz	49.158	59.864	-10.706	36.885	49.864	-12.979	19.725
366 kHz	44.822	58.591	-13.769	28.828	48.591	-19.763	19.852
453.999 kHz	44.416	56.802	-12.386	21.917	46.802	-24.885	19.916
514 kHz	45.505	56	-10.495	26.16	46	-19.84	19.908
558 kHz	49.196	56	-6.804	32.673	46	-13.327	19.91
630 kHz	49.137	56	-6.863	33.726	46	-12.274	19.867
646 kHz	47.286	56	-8.714	26.505	46	-19.495	19.852
670 kHz	43.036	56	-12.964	20.2	46	-25.8	19.834
730 kHz	44.006	56	-11.994	24.705	46	-21.295	19.807
970 kHz	42.197	56	-13.803	20.543	46	-25.457	19.729
4.104 MHz	48.948	56	-7.052	34.236	46	-11.764	19.764
17.584 MHz	46.016	60	-13.984	30.863	50	-19.137	20.592



3.6. CONCLUSION

The sample of the equipment **Tikee 4**, Sn : **T-4TK-4Q-E01492**, tested in the configuration presented in this test report **satisfies** to requirements of the product family standard applied (See §Test Program) for conducted emissions.

4. MEASUREMENT OF RADIATED EMISSION

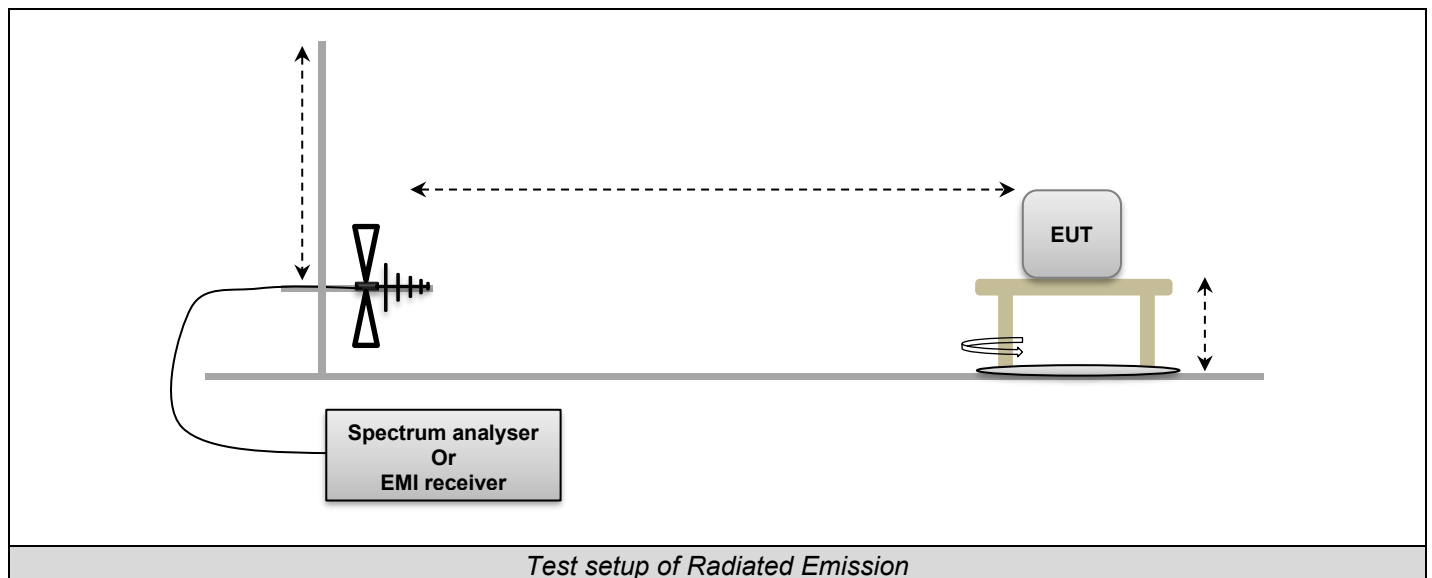
4.1. TEST CONDITIONS

Date of test : November 06, 2024
 Test performed by : Akram HAKKARI
 Relative humidity (%) : 33
 Ambient temperature (°C) : 21

4.2. TEST SETUP

Test procedure:
 ANSI C63.4 & FCC Part 15 subpart B

The EUT and auxiliaries are set 80cm above the ground on the non-conducting table (Table-top equipment).
 The EUT is powered by V_{nom} .



Same setup is used in semi anechoic chamber during pre-characterization, with a distance of 3m between EUT and antenna.





Photo on OATS



4.3. TEST METHOD

During pre-characterization, a pre-scan of all the setup has been performed on all axis of EUT used in normal configuration. The pre-characterization graphs are obtained in PEAK detection, and AVERAGE detection for frequencies above 1GHz. A summary of the worst case emissions found in all test configurations and modes is shown. Spurious or frequency band are measured with qualification method to show compliance with limits.

Following frequency ranges, test setup parameters are different and specified in tables below.

4.3.1. 30MHz –1GHz

Frequency range:	30MHz to 1GHz	
Test:	Pre-Characterization	Qualification
Antenna Polarization:	Horizontal and Vertical	
Antenna Height:	Centered on EUT	Varied by step from 1m to 4m
Antenna Type:	Bi-Log	Bi-Log
Min. Antenna Beamwidth:	Teseq CBL 6111 / w@3m - 4.2m<1GHz	Teseq CBL 6111 / w@10m - 14m<1GHz
RBW Filter:	100kHz	100kHz
Maximization:	Turntable rotation of 360 degrees range	
Test site:	Full Anechoic Chamber	Open Aera Test Site
Distance EUT - Antenna:	3m	10m
Detector:	QPeak	QPeak
Mode:	Linear Scan	

4.3.2. 1GHz – 14GHz:

Frequency range:	1GHz to 6GHz	
Test:	Pre-Characterization	Qualification
Antenna Polarization:	Horizontal and Vertical	
Antenna Height:	Centered on EUT	Centered on EUT
Antenna Type:	Horn	Horn
Min. Antenna Beamwidth:	Teseq CBL 6143 / w@3m - 2.5m>1GHz	Teseq CBL 6143 / w@3m - 2.5m>1GHz
RBW Filter:	1MHz	1MHz
Maximization:	Turntable rotation of 360 degrees range	
Test site:	Full Anechoic Chamber	Full Anechoic Chamber
Distance EUT - Antenna:	3m	3m
Detector:	Peak & Average	Peak & Average
Mode:	Linear Scan	



4.4. TEST EQUIPMENT LIST

TEST EQUIPMENT USED					
Description	Manufacturer	Model	Identifier	Cal_Date	Cal_Due
Amplifier 10MHz - 18GHz	LCIE SUD EST	—	A7102082	05/22	09/24
Antenna Bi-log	AH System	SAS-521-7	C2040180	05/23	05/25
Antenna horn 18GHz	EMCO	3115	C2042027	04/22	04/25
BAT EMC	NEXIO	v3.21.0.32	L1000115	-/-	-/-
CABLE	TELEDYNE	R82-0404-0.5M	A5330010	03/22	03/25
Cable 0.75m	-	18GHz	A5329900	08/24	08/26
Cable SMA 40cm	WITHWAVE	W101-SM1-0.4M	A5329979	10/23	10/26
CONTROLLER	INNCO	CO3000	D3044034	-/-	-/-
Emission Cable (SMA 1m)	TELEDYNE	26GHz	A5329874	08/22	08/25
Emission Cable (SMA 3.3m)	TELEDYNE	26GHz	A5329875	08/22	08/25
Filter Matrice	LCIE SUD EST	Combined filters	A7484078	03/23	03/25
Multimeter - CEM	FLUKE	87	A1240251	10/23	10/25
Rehausse Table C3	LCIE	—	F2000511	-/-	-/-
Rehausse Table C3	LCIE	—	F2000507	-/-	-/-
Semi-Anechoic chamber #3 (BF)	SIEPEL	—	D3044017_BF	04/22	04/25
Semi-Anechoic chamber #3 (VSWR)	SIEPEL	—	D3044017_VSWR	04/22	04/25
Spectrum analyzer	ROHDE & SCHWARZ	FSU 26	A4060058	09/23	09/25
Table C3	LCIE	—	F2000461	-/-	-/-
Thermo-hygrometer (PM1/2/3)	KIMO	HQ 210	B4206022	05/23	05/25
TILT	INNCO	TILT	D3044033	-/-	-/-
Turntable chamber (Cage#3)	ETS Lingren	Model 2165	F2000371	-/-	-/-
Turntable controller (Cage#3)	ETS Lingren	Model 2090	F2000444	-/-	-/-
Antenna Mat (OATS)	ETS Lingren	2071-2	F2000392	-/-	-/-
Biconic Antenna	EATON	94455-1	C2040234	05/23	05/25
Cable (OATS)	—	1GHz	A5329623	09/24	09/25
Emission Cable	CABELTEL	6GHz	A5329069	02/24	02/25
Emission Cable	MICRO-COAX	1GHz	A5329656	09/24	09/25
Emission Cable	RADIALEX	-/-	A5329061	07/24	07/25
OATS	—	—	F2000409	07/24	07/25
Rehausse Table C1/OATS	LCIE	—	F2000512	-/-	-/-
Table C1/OATS	LCIE	—	F2000445	-/-	-/-
Turntable (OATS)	ETS Lingren	Model 2187	F2000403	-/-	-/-
Turntable / Mast controller (OATS)	ETS Lingren	Model 2066	F2000372	-/-	-/-

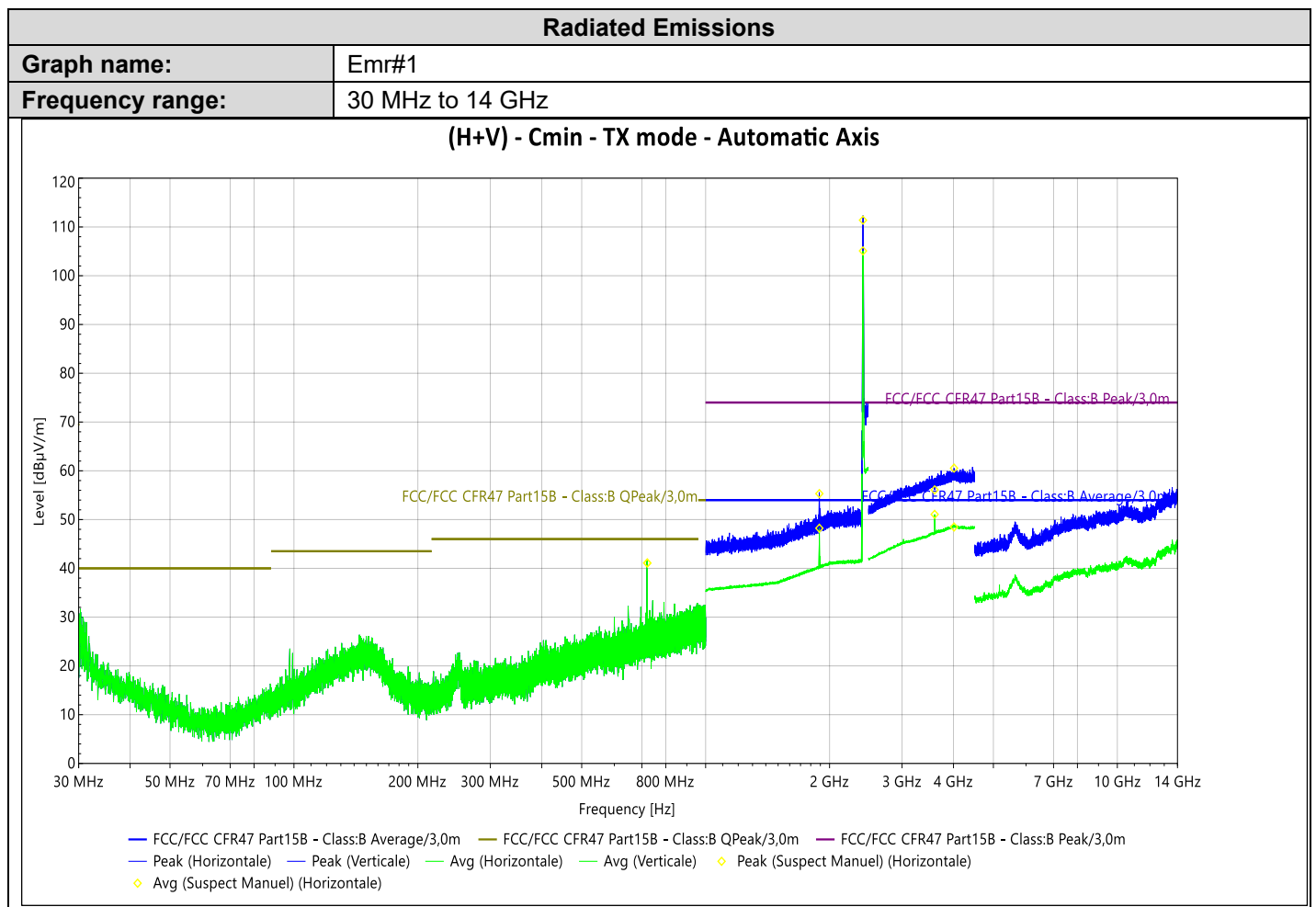
4.5. DIVERGENCE, ADDITION OR SUPPRESSION ON THE TEST SPECIFICATION

None

4.6. TEST RESULTS – RUNNING MODE N°1

4.6.1. 30MHz –14GHz

Graph identifier	Polarization	Mode	Channel	EUT position	Comments
Emr# 1	H/V	TX	Cmin	Axis XY/Z	See the following results



Pre-Characterization:

Frequency	PK Level (dBμV/m)	Lim.PK (dBμV/m)	Avg (dBμV/m)	Lim.Avg (dBμV/m)	Lim.QP (dBμV/m)	Angle (°)	Polar.	Correct. (dB)
2.4109385 GHz*	111.39	74.00	105.09	54.00		62	H	35.72
721.5615 MHz	41.09		41.09		46.00	359	H	26.49
1.889 GHz	55.32	74.00	48.23	54.00		0	H	34.68
3.599834399 GHz	56.09	74.00	51.07	54.00		332	H	40.39
4.0124103 GHz	60.55	74.00	48.48	54.00		96	H	41.72

*Carrier frequency



Qualification :

Test Frequency (MHz)	Meter Reading dB(μV)	Detector (Pk/QP/Av)	Polarity (V/H)	Transducer Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Margin (dB)
721.5600	22.6	QP	V	29.2	51.8	56.9	-5.1

4.7. CONCLUSION

The sample of the equipment **Tikee 4**, Sn : **T-4TK-4Q-E01492**, tested in the configuration presented in this test report **satisfies** to requirements of the product family standard applied (See §Test Program) for radiated emissions.

5. UNCERTAINTIES CHART

Type de mesure / Kind of measurement	Incertitude élargie laboratoire / Wide uncertainty laboratory (k=2) $\pm x$	Incertitude limite du CISPR / CISPR uncertainty limit $\pm y$
Mesure des perturbations conduites en tension sur le réseau d'énergie (monophasé /triphase) 9kHz-150kHz <i>Measurement of conducted disturbances in voltage on the power port (single & three phases)9kHz-150kHz</i>	3.7dB	3.8dB
Mesure des perturbations conduites en tension sur le réseau d'énergie (monophasé /triphase) 150kHz-30MHz <i>Measurement of conducted disturbances in voltage on the power port (single & three phases)150kHz-30MHz</i> LISN 50Ω/50μH Capacitive Voltage Probe	3.3dB 3.7dB	3.4dB 3.9dB
Mesure des perturbations conduites en tension sur le réseau de télécommunication <i>Measurement of conducted disturbances in voltage on the telecommunication port.</i> AAN avec aLCL = 55 ... 40 dBc AAN avec aLCL = 65 ... 50 dBc AAN avec aLCL = 75 ... 60 dBc	4.2dB 4.6dB 5.0dB	4.2dB 4.6dB 5.1dB
Mesure des perturbations discontinues conduites en tension <i>Measurement of discontinuous conducted disturbances in voltage</i>	3.4dB	3.4dB
Mesure des perturbations conduites en courant <i>Measurement of conducted disturbances in current</i>	2.9dB	2.9dB
Mesure du champ électrique rayonné en cage de Faraday semi-anéchoïque de 30MHz à 1GHz <i>Measurement of radiated electric field in half-anechoic Faraday room</i> <i>From 30MHz to 1GHz</i>	6.3dB	6.3dB
Mesure du champ électrique rayonné en cage de Faraday anéchoïque de 1GHz à 6GHz <i>Measurement of radiated electric field in full-anechoic Faraday room</i> <i>From 1GHz to 6GHz</i>	5.2dB	5.2dB
Mesure du champ électrique rayonné en cage de Faraday anéchoïque de 6GHz à 18GHz <i>Measurement of radiated electric field in full-anechoic Faraday room</i> <i>From 6GHz to 18GHz</i>	5.5dB	5.5dB
Mesure du champ électrique rayonné sur le site en espace libre de Moirans 30MHz – 1GHz. <i>Measurement of radiated electric field on the Moirans open area test site</i> <i>30MHz – 1GHz.</i>	6.3dB	6.3dB
Mesure du champ électrique rayonné IN SITU de 30 à 1000 MHz <i>IN SITU measurement of radiated electric field from 30 to 1000MHz</i>	A l'étude / Under consideration	5.2dB
Mesure de la puissance perturbatrice <i>Measurement of disturbance power</i>	3.32dB	4.5dB
Mesure des harmoniques de courant <i>Measurement of current harmonics</i>	11.11%	/
Mesure du flicker <i>Flicker measurement</i>	9.26%	/

Les valeurs d'incertitudes calculées du laboratoire étant inférieures aux valeurs d'incertitudes limites établies par le CISPR, la conformité de l'échantillon est établie directement par les niveaux limites applicables. Ce tableau regroupe l'ensemble des incertitudes maximales pour les essais réalisables dans le laboratoire, qu'ils aient été ou non réalisés dans le cadre du présent rapport / *The uncertainty values calculated by the laboratory are lower than limit uncertainty values defined by the CISPR. The conformity of the sample is directly established by the applicable limits values. This table includes all uncertainties maximum feasible for testing in the laboratory, whether or not made in this report*

Note - L'incertitude de mesure instrumentale est déterminée selon la CISPR 16-4-2. / *The instrumentation measurement uncertainty is determined according to CISPR16-4-2*